

**CHE323/384 Chemical Processes for Micro- and Nanofabrication**  
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Homework #10

1. A photoresist gives a final resist thickness of 320 nm when spun at 2800 rpm.
  - a) What spin speed should be used if a 290-nm-thick coating of this same resist is desired?
  - b) If the maximum practical spin speed for 200-mm wafers is 4000 rpm, at what thickness would a lower viscosity formulation of the resist be required?
2. Complimentary mask features (for example, an isolated line and an isolated space of the same width) are defined by

$$t_m^c(x, y) = 1 - t_m(x, y)$$

Prove that the diffraction patterns of complimentary mask features are given by

$$T_m^c(f_x, f_y) = \delta(f_x, f_y) - T_m(f_x, f_y)$$

Use this expression to derive the diffraction pattern of an isolated line.

3. Show that the Fourier transform is a linear operation, that is, show that for two functions  $f(x, y)$  and  $g(x, y)$ , and two constants  $a$  and  $b$ ,

$$\mathcal{F}\{af(x, y) + bg(x, y)\} = aF(f_x, f_y) + bG(f_x, f_y)$$

4. Prove the shift theorem of the Fourier transform:

$$\text{If } \mathcal{F}\{g(x, y)\} = G(f_x, f_y), \quad \mathcal{F}\{g(x - a, y - b)\} = G(f_x, f_y)e^{-i2\pi(f_x a + f_y b)}$$

5. Prove the similarity theorem of the Fourier transform:

$$\text{If } \mathcal{F}\{g(x, y)\} = G(f_x, f_y), \quad \mathcal{F}\{g(ax, by)\} = \frac{1}{|ab|} G\left(\frac{f_x}{a}, \frac{f_y}{b}\right)$$